

# AUTOMOTIVE CURRENT TRANSDUCER OPEN LOOP TECHNOLOGY

HSTDR 300-000, HSTDR 400-000, HSTDR 600-000, HSTDR 900-000, HSTDR 1000-000, HSTDR 1200-000, HSTDR 1200/SP1-000, HSTDR 1300-000, HSTDR 1500-000



## Introduction

The HSTDR-000 family is a transducer for DC, AC, or pulsed currents measurement in high power and low voltage automotive applications. It offers a galvanic separation between the primary circuit (high power) and the secondary circuit (electronic circuit).

The HSTDR-000 family gives you a choice of having different current measuring ranges in the same housing (from  $\pm 300$  A up to  $\pm 1500$  A).

## Features

- Open Loop transducer using the Hall effect sensor
- High insulation level
- Unipolar +5 V DC power supply
- Primary current measuring range up to  $\pm 1500$  A
- Operating temperature range:  $-40\text{ }^{\circ}\text{C} < T < +125\text{ }^{\circ}\text{C}$
- Output voltage: fully ratio-metric (in sensitivity and offset).

## Advantages

- Excellent accuracy
- Very good linearity
- Very low thermal offset drift
- Very low thermal sensitivity drift
- High frequency bandwidth
- No insertion losses
- Very fast delay time.

## Automotive applications

- Starter Generators
- Inverters
- HEV applications
- EV applications
- DC / DC converters
- DC link.

## Principle of HSTDR-000 family

The open loop transducers uses a Hall effect integrated circuit. The magnetic flux density  $B$ , contributing to the rise of the Hall voltage, is generated by the primary current  $I_p$  to be measured.

The current to be measured  $I_p$  is supplied by a current source i.e. battery or generator (Figure 1).

Within the linear region of the hysteresis cycle,  $B$  is proportional to:

$$B(I_p) = a \times I_p$$

The Hall voltage is thus expressed by:

$$U_{\text{Hall}} = (c_{\text{Hall}} / d) \times I_{\text{Hall}} \times a \times I_p$$

Except for  $I_p$ , all terms of this equation are constant. Therefore:

$$U_{\text{Hall}} = b \times I_p$$

$a$  constant

$b$  constant

$c_{\text{Hall}}$  Hall coefficient

$d$  thickness of the Hall plate

$I_{\text{Hall}}$  current across the Hall plates

The measurement signal  $U_{\text{Hall}}$  amplified to supply the user output voltage or current.

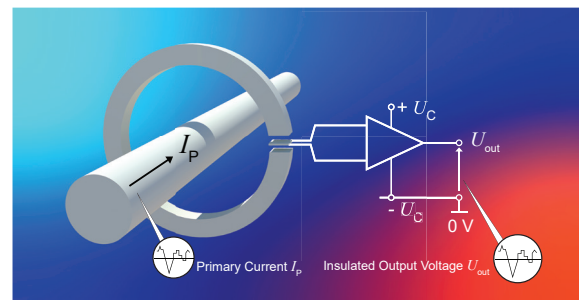
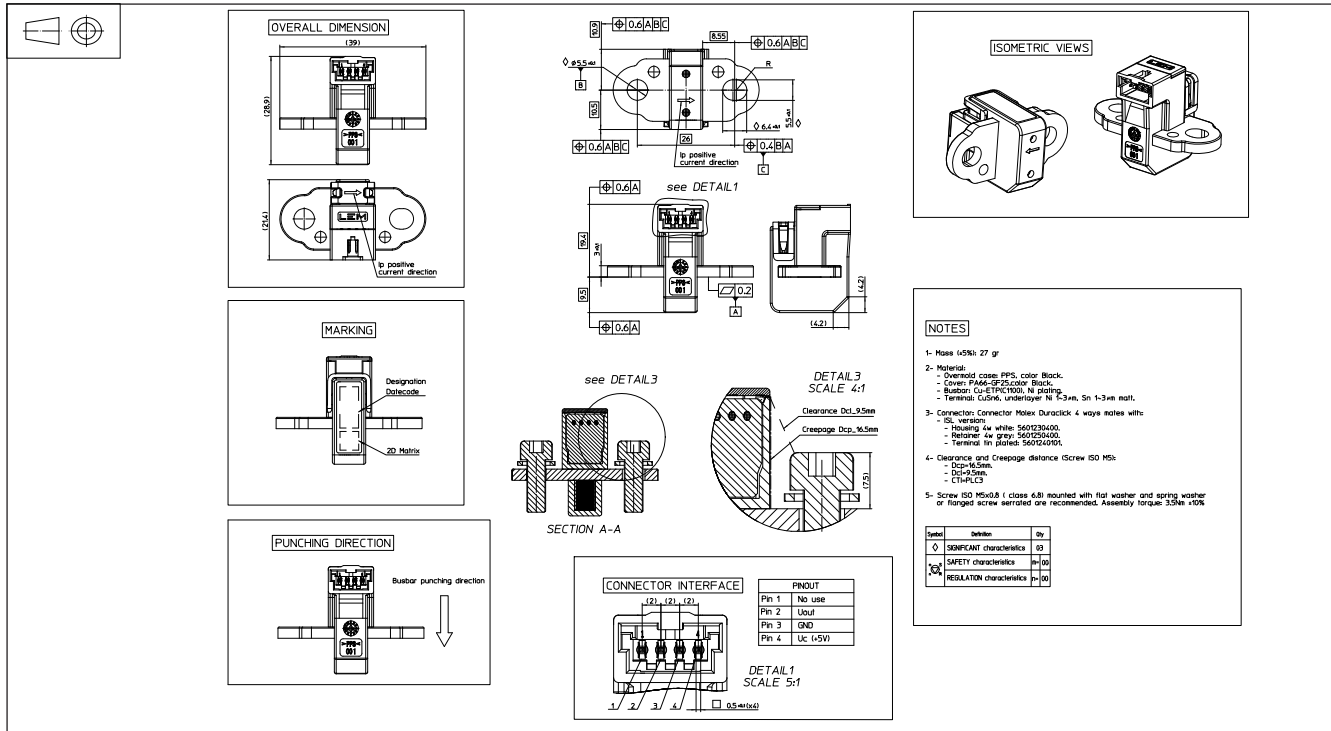
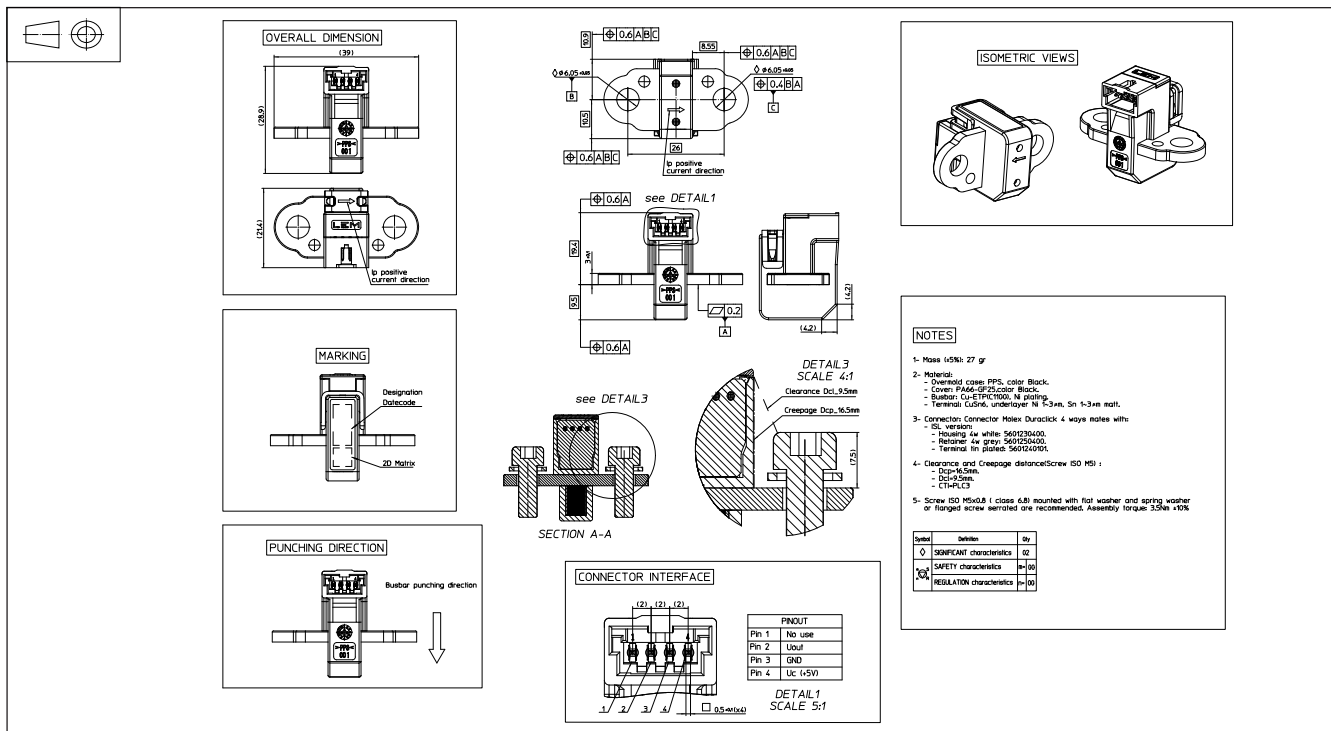


Fig. 1: Principle of the open loop transducer.

**Dimensions (in mm)**
**HSTR 300-000, HSTR 400-000, HSTR 600-000, HSTR 900-000, HSTR 1000-000, HSTR 1200-000, HSTR 1300-000, HSTR 1500-000**

**Dimensions (in mm)**
**HSTR 1200/SP1-000**

**Mechanical characteristics**

Refer to Outline Drawing.

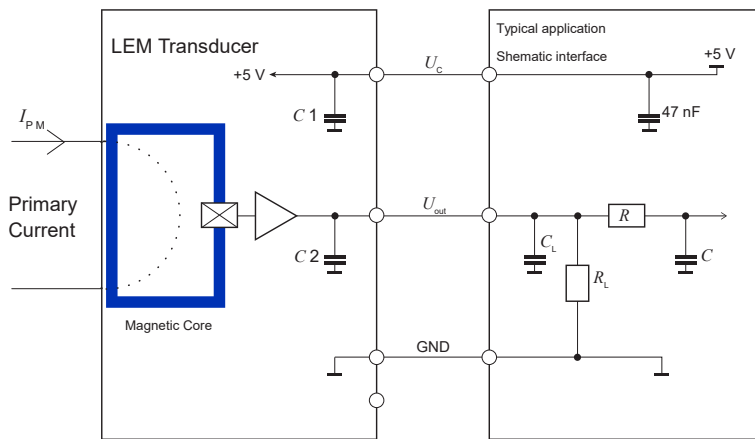
**Remark**

- $U_{out} > U_0$  when  $I_p$  flows in the positive direction (see arrow on drawing).

**Mounting recommendation**

Assembly refer to Outline Drawing.

Electronic recommendation



$R_L > 10 \text{ k}\Omega$  optional resistor for signal line diagnostic (optional)  
 $C_L < 2.2 \text{ nF}$  EMC protection (optional)  
 RC: low pass filter (optional)

**Absolute ratings (not operating)**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
Maximum supply voltage	$U_{C\ max}$	V	0		8	Continuous, not operating
					6.5	Exceeding this voltage may temporarily reconfigure the circuit until $U_C$ comes back to 5 V
Ambient storage temperature	$T_{A\ st}$	°C	-40		125	
Electrostatic discharge voltage (HBM - Human Body Model)	$U_{ESD\ HBM}$	kV			8	
RMS voltage for AC insulation test	$U_d$	kV			4.7	50 Hz, 1 min, IEC 60664 part1
Creepage distance	$d_{Cp}$	mm	16.5			
Clearance	$d_{Cl}$	mm	9.5			
Comparative tracking index	$CTI$	-	PLC3			
Maximum output current	$I_{out\ max}$	mA	-10		10	
Maximum output voltage	$U_{out\ max}$	V	-0.5		$U_C + 0.5$	
Insulation resistance	$R_{INS}$	MΩ	500			1000 V DC

**Operating characteristics in nominal range ( $I_{PN}$ )**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Supply voltage <sup>1)</sup>	$U_C$	V	4.75	5	5.25	
Ambient operating temperature <sup>2)</sup>	$T_A$	°C	-40		125	
Load capacitance	$C_L$	nF			2.2	
Output voltage (Analog)	$U_{out}$	V	$U_{out} = (U_C / 5) \times (U_O + S \times I_P)$			
Offset voltage	$U_O$	V		2.5		@ $U_C = 5\ V$
Current consumption	$I_C$	mA		15		@ $U_C = 5\ V$ , @ $T_A = 25\ °C$
Load resistance	$R_L$	KΩ	10			
Output internal resistance	$R_{out}$	Ω			10	DC to 1 KHz
<b>Performance Data</b>						
Ratiometricity error	$\epsilon_r$	%		±0.3		@ $T_A = 25\ °C$
Sensitivity error	$\epsilon_S$	%		±1		@ $T_A = 25\ °C$ , @ $U_C = 5\ V$
Electrical offset voltage	$U_{OE}$	mV		±4		@ $T_A = 25\ °C$ , @ $U_C = 5\ V$
Magnetic offset voltage	$U_{OM}$	mV		±2		@ $T_A = 25\ °C$ , @ $U_C = 5\ V$
Average temperature coefficient of $U_{OE}$	$TCU_{OE\ AV}$	mV/°C	-0.08	±0.04	0.08	@ $-40\ °C < T_A < 125\ °C$
Average temperature coefficient of $S$	$TCS_{AV}$	%/°C	-0.03	±0.01	0.03	@ $-40\ °C < T_A < 125\ °C$
Linearity error	$\epsilon_L$	% $I_{PM}$		±1		@ $U_C = 5\ V$ , @ $T_A = 25\ °C$ , @ $I_P = I_{PM}$
Delay time to 90 % of the final output value for $I_{PN}$ step	$t_{D\ 90}$	μs		2	6	$di/dt = 100\ A/\mu s$
Frequency bandwidth <sup>3)</sup>	$BW$	kHz	40			@ -3 dB
Peak-to-peak noise voltage	$U_{no\ pp}$	mV		9		@ DC to 1 MHz for HSTDR 1500-000
Peak-to-peak noise voltage	$U_{no\ pp}$	mV		22		@ DC to 1 MHz for HSTDR 300-000
Phase shift	$\Delta\phi$	°	-4			@ 1 kHz

Notes: <sup>1)</sup> The output voltage  $U_{out}$  is fully ratiometric. The offset and sensitivity are dependent on the supply voltage  $U_C$  relative to the following formula:

$$I_P = \left( \frac{5}{U_C} \times U_{out} - U_O \right) \times \frac{1}{S} \text{ with } S \text{ in (V/A)}$$

<sup>2)</sup> Absolute maximum ambient operating temperature (include busbar): +150 °C

<sup>3)</sup> Primary current frequencies must be limited in order to avoid excessive heating of the sensor higher than 125 °C.

**HSTDR 300-000**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Primary current, measuring range	$I_{PM}$	A	-300		300	
Sensitivity	$S$	mV/A		6.67		@ $U_c = 5\text{ V}$

**HSTDR 400-000**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Primary current, measuring range	$I_{PM}$	A	-400		400	
Sensitivity	$S$	mV/A		5		@ $U_c = 5\text{ V}$

**HSTDR 600-000**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Primary current, measuring range	$I_{PM}$	A	-600		600	
Sensitivity	$S$	mV/A		3.33		@ $U_c = 5\text{ V}$

**HSTDR 900-000**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Primary current, measuring range	$I_{PM}$	A	-900		900	
Sensitivity	$S$	mV/A		2.22		@ $U_c = 5\text{ V}$

**HSTDR 1000-000**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Primary current, measuring range	$I_{PM}$	A	-1000		1000	
Sensitivity	$S$	mV/A		2		@ $U_c = 5\text{ V}$

**HSTDR 1200-000, HSTDR 1200/SP1-000**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Primary current, measuring range	$I_{PM}$	A	-1200		1200	
Sensitivity	$S$	mV/A		1.67		@ $U_c = 5\text{ V}$

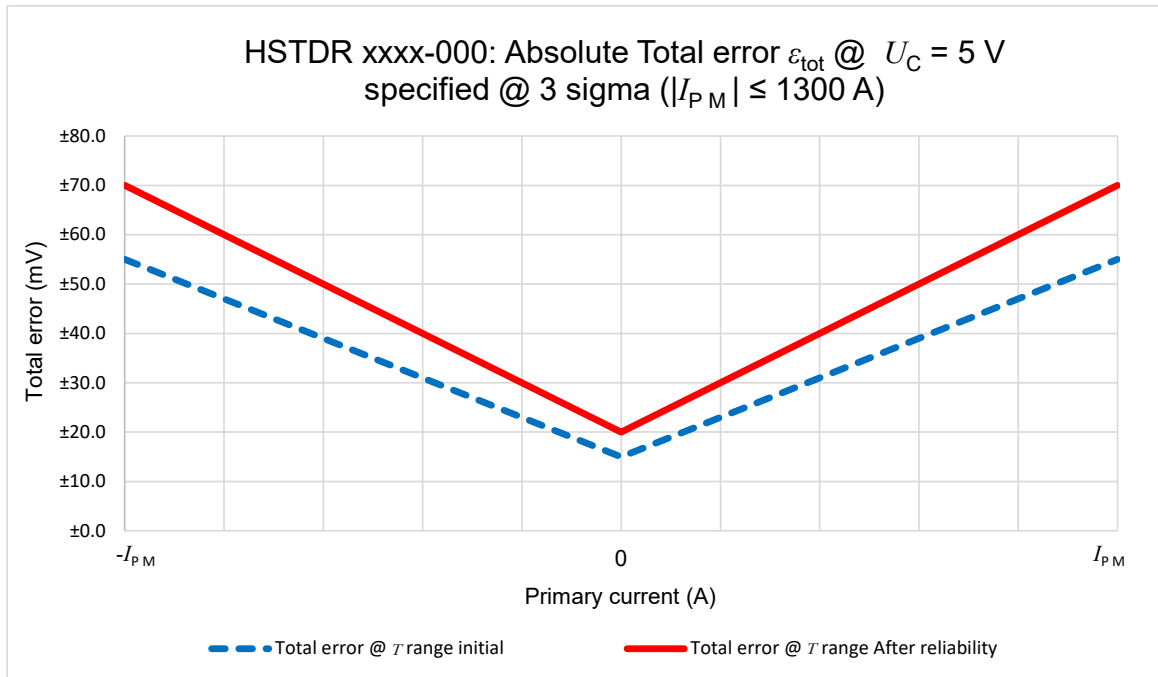
**HSTDR 1300-000**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Primary current, measuring range	$I_{PM}$	A	-1300		1300	
Sensitivity	$S$	mV/A		1.54		@ $U_c = 5\text{ V}$

**HSTDR 1500-000**

Parameter	Symbol	Unit	Specification			Conditions
			Min	Typical	Max	
<b>Electrical Data</b>						
Primary current, measuring range	$I_{PM}$	A	-1500		1500	
Sensitivity	$S$	mV/A		1.33		@ $U_c = 5\text{ V}$

Total error



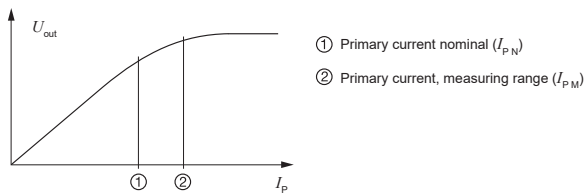
Primary current (A)	Total error $T = 25\text{ °C}$ , $U_C = 5\text{ V}$ initial		Total error $-40\text{ °C} \leq T \leq 125\text{ °C}$ , $U_C = 5\text{ V}$ initial		Total error $T = 25\text{ °C}$ , $U_C = 5\text{ V}$ After reliability		Total error $-40\text{ °C} \leq T \leq 125\text{ °C}$ , $U_C = 5\text{ V}$ After reliability	
	(mV)	(%)	(mV)	(%)	(mV)	(%)	(mV)	(%)
$-I_{PM} \geq -1300$	±40	±2 %	±55	±2.75 %	±65	±3.25 %	±70	±3.5 %
0	±10	±0.5 %	±15	±0.75 %	±15	±0.75 %	±20	±1 %
$I_{PM} \leq 1300$	±40	±2 %	±55	±2.75 %	±65	±3.25 %	±70	±3.5 %
$-1500 \leq -I_{PM} < -1300$	±55	±2.75 %	±70	±3.5 %	±65	±3.25 %	±70	±3.5 %
$1500 \geq I_{PM} > 1300$	±55	±2.75 %	±70	±3.5 %	±65	±3.25 %	±70	±3.5 %

Remark

Specific application, please refer to LEM document 'Application Note N°ANE230327' available on our Web site:  
[https://www.lem.com/sites/default/files/marketing/hstdr\\_hsndr\\_ham\\_application\\_note\\_v0.pdf](https://www.lem.com/sites/default/files/marketing/hstdr_hsndr_ham_application_note_v0.pdf)

**PERFORMANCES PARAMETERS DEFINITIONS**

**Primary current definition:**



**Definition of typical, minimum and maximum values:**

Minimum and maximum values for specified limiting and safety conditions have to be understood as such as values shown in “typical” graphs. On the other hand, measured values are part of a statistical distribution that can be specified by an interval with upper and lower limits and a probability for measured values to lie within this interval. Unless otherwise stated (e.g. “100 % tested”), the LEM definition for such intervals designated with “min” and “max” is that the probability for values of samples to lie in this interval is 99.73 %. For a normal (Gaussian) distribution, this corresponds to an interval between -3 sigma and +3 sigma. If “typical” values are not obviously mean or average values, those values are defined to delimit intervals with a probability of 68.27 %, corresponding to an interval between -sigma and +sigma for a normal distribution. Typical, minimum and maximum values are determined during the initial characterization of a product.

**Output noise voltage:**

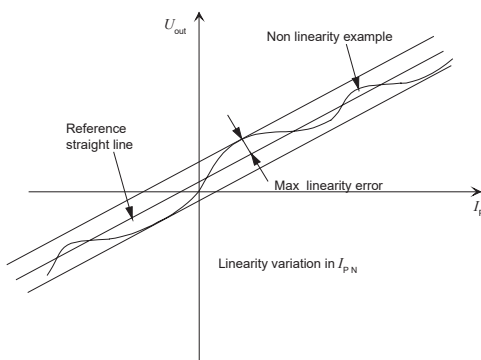
The output voltage noise is the result of the noise floor of the Hall elements and the linear amplifier.

**Magnetic offset:**

The magnetic offset is the consequence of an any current on the primary side. It’s defined after a stated excursion of primary current.

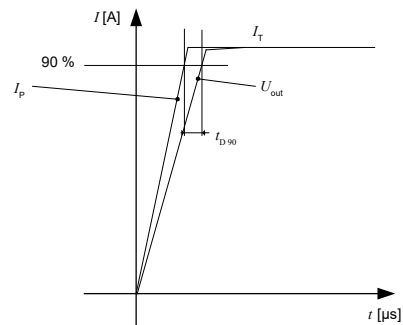
**Linearity:**

The maximum positive or negative discrepancy with a reference straight line  $U_{out} = f(I_p)$ .  
Unit: linearity (%) expressed with full scale of  $I_{pN}$ .



**Response time (delay time)  $t_{D90}$ :**

The time between the primary current signal ( $I_{pN}$ ) and the output signal reach at 90 % of its final value.



**Sensitivity:**

The transducer’s sensitivity  $S$  is the slope of the straight line

$U_{out} = f(I_p)$ , it must establish the relation:

$$U_{out}(I_p) = U_C / 5 (S \times I_p + U_O)$$

**Offset with temperature:**

The error of the offset in the operating temperature is the variation of the offset in the temperature considered with the initial offset at 25 °C.

The offset variation  $I_{OT}$  is a maximum variation the offset in the temperature range:

$$I_{OT} = I_{OE \max} - I_{OE \min}$$

The offset drift  $TCI_{OE \text{ AV}}$  is the  $I_{OT}$  value divided by the temperature range.

**Sensitivity with temperature:**

The error of the sensitivity in the operating temperature is the relative variation of sensitivity with the temperature considered with the initial offset at 25 °C.

The sensitivity variation  $S_T$  is the maximum variation (in ppm or %) of the sensitivity in the temperature range:

$$S_T = (\text{Sensitivity max} - \text{Sensitivity min}) / \text{Sensitivity at } 25 \text{ }^\circ\text{C}.$$

The sensitivity drift  $TCS_{AV}$  is the  $S_T$  value divided by the temperature range. Deeper and detailed info available is our LEM technical sales offices ([www.lem.com](http://www.lem.com)).

**Offset voltage @  $I_p = 0 \text{ A}$ :**

The offset voltage is the output voltage when the primary current is zero. The ideal value of  $U_O$  is  $U_C / 2$ . So, the difference of  $U_O - U_C / 2$  is called the total offset voltage error. This offset error can be attributed to the electrical offset (due to the resolution of the ASIC quiescent voltage trimming), the magnetic offset, the thermal drift and the thermal hysteresis. Deeper and detailed info available is our LEM technical sales offices ([www.lem.com](http://www.lem.com)).

**Environmental test specifications:**

Refer to LEM GROUP test plan laboratory CO.11.11.515.0 with “Tracking\_Test Plan\_Auto” sheet.

**Validation test specifications**

Name	Standard	Condition
<b>ELECTRICAL TESTS</b>		
Frequency bandwidth	LEM 98.20.00.538.0	30 Hz to 100 kHz; At 20 A peak ; ≥ 40 kHz @ -3 dB
Phase delay	LEM 98.20.00.538.0	Power supply 5 V, $I_p = 0$ A 30 Hz to 100 kHz; At 20 A peak
Output voltage Noise (peak-to-peak)	LEM 98.20.00.575.0	Sweep from DC to 1 MHz
Delay time ; $di/dt$	LEM 98.20.00.545.0	100 A/μs ; $t_{D90}$ of $I_{PN} \leq 6$ μs
$du/dt$	LEM 98.20.00.545.0	Slope: 5 kV/μs $U = 1000$ V
<b>ENVIRONMENTAL TESTS</b>		
Ageing 85 °C /85 % RH	JESD 22-A101 (03/2009)	85 °C/85 % RH; Duration = 1000 h; Power supply 5 V ; primary current 0 A; Monitoring output 1 time/hr
Low temperature operating endurance	ISO 16750-4 § 5.1.1.2 (04/2010)	-40 °C, 24 h; Power supply 5 V Monitoring: 2 times/hr
High temperature operating endurance	ISO 16750-4 § 5.1.2.2 (04/2010)	Temperature 125 °C; 96 h; power supply 5 V Monitoring 2 times/hr
High temperature storage	AQG 324 (2019) § 9.4	$T = 125$ °C; Duration = 1000 h; $U_C =$ no powersupply ( unconnected)
Low temperature storage	ISO 16750-4 5.1.1.1(2006)	$T = -40$ °C; Duration = 1000 h; $U_C =$ no powersupply ( unconnected)
Humidity heat, cyclic test: Test 2 Composite temperature/humidity cyclic test	ISO 16750-4 § 5.6.2.3 (04/2010)	Temperature range -10 °C/ +65 °C, 93 % RH Duration = 240 h (10 cycles)
Thermal shock	ISO 16750-4 § 5.3.2 (04/2010)	Temperature range -40 °C& 125 °C, 300 cycles; 40 min/40 min, no power supply
Sinus Vibration	ISO 16750-3 § 4.1.2.2.2.2 (12/2012)	Monitoring $U_C$ and $U_{out}$ is mandatory, Temperature -40/125 °C, 22 H/axis, 100 Hz to 440 Hz Sweep: ≤ 0.5 oct/min
Random Vibration	ISO 16750-3 § 4.1.2.2.2.3 (12/2012)	Monitoring $U_C$ and $U_{out}$ is mandatory, Temperature -40/125 °C, 22 H/ axis, 10 to 2000 Hz 10 G (RMS)
Mechanical Shocks	ISO 16750-3 § 4.2.2 (12/2012)	Operating mode: 3.2 Pulse shape: half sine, 50 G, 6 ms 10 shocks per direction (total 60)
Free Fall	ISO 16750-3 § 4.3 (12/2012)	3 pcs, Falls/DUT: 2 times, Height = 1 m 3 axes, 2 directions by axis, Operating mode: 1.1
Cross section checking on PCBA	IPC-A-610G: 2017 Class 3W	IPC-TM-650 2.1.1F:2015
Cross section checking on solderless connections	GB/T 18290.5-2015	IPC-TM-650 2.1.1F:2015
Whisker checking on PCBA	Refer to JESD201-A (04/2010)	Refer to JESD22-A121A (04/2010) Class 2
<b>INSULATION TESTS</b>		
Dielectric withstand voltage	ISO 16750-2 § 4.11 (11/2012)	4.7 kV test voltage, time = 60 s, No dielectric breakdown, no flash-over, functional after test
Insulation test	ISO 16750-2 § 4.12 (11/2012)	1000 V DC, time = 60 s, $R_{INS} \geq 500$ MΩ Minimum



**EMC TESTS**

Immunity to Electrostatic Discharges (Handling of devices)	ISO 10605 (07/2008)	Discharge module: 150 pF/2000 Ω Contact discharges: ±4.6 kV, Air discharges: ±8 kV $U_c$ = NO power supply, Criteria B
Immunity to Radiated disturbances (ALSE)	ISO 11452-2 (2019)	Power supply: 5 V $f$ = 400 MHz to 1 GHz; Level = 100 V/m (CW, AM 80 %) $f$ = 0.8 GHz to 2 GHz; Level = 70 V/m (CW, PM PRR = 217 Hz) $f$ = 1 GHz to 2 GHz; Level = 70 V/m (CW) Criteria A acceptance @ 5 % of 2 V
Immunity to Conducted disturbances (BCI)	ISO 11452-4 (12/2011)	Level = see Annex E Fig. & Table E.1 (Test Level II) $f$ = 1 MHz to 400 MHz Criteria A acceptance @ 5 % of 2 V
Emission Radiated (ALSE)	CISPR 25 §6.5 (2016)	Table 7, Class 5 by default $f$ = 150 kHz to 2.5 GHz Load simulator will be provided (R&D)